

| | | | | |
|-----------------------------------|---------------------------------------|--|--|-------------|
| Notice of References Cited | Application/Control No. 10/724,552 | | Applicant(s)/Patent Under Reexamination KOSTRZEWSKI ET AL. | |
| | Examiner Sheela C. Chawan | | Art Unit 2624 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| * | A | US-4,588,260 | 05-1986 | Horner, Joseph L. | 359/29 |
| | B | US-5,668,648 | 09-1997 | Saito et al. | 359/9 |
| | C | US-5,933,515 | 08-1999 | Pu et al. | 382/124 |
| | D | US-6,229,906 B1 | 05-2001 | Pu et al. | 382/116 |
| | E | US-6,185,319 B1 | 02-2001 | Fujiwara, Hisatoshi | 382/127 |
| | F | US-6,424,729 B1 | 07-2002 | Soon, Boon Yi | 382/124 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.